

# N-Channel 600V (D-S) Super Junction Power MOSFET

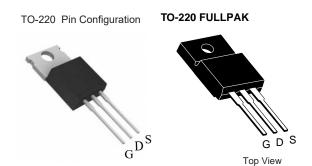
PRODUCT SUMMARY				
V <sub>DS</sub> (V) at T <sub>J</sub> max.	600			
R <sub>DS(on)</sub> max. at 25 °C (Ω)	V <sub>GS</sub> = 10 V	0.19		
Q <sub>g</sub> max. (nC)	70			
Q <sub>gs</sub> (nC)	7.8			
Q <sub>gd</sub> (nC)	9			
Configuration	Single			

#### **FEATURES**

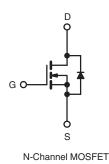
- Low figure-of-merit (FOM) Ron x Qq
- Low input capacitance (Ciss)
- Reduced switching and conduction losses
- Ultra low gate charge (Q<sub>q</sub>)
- Avalanche energy rated (UIS)

#### **APPLICATIONS**

- Server and telecom power supplies
- Switch mode power supplies (SMPS)
- Power factor correction power supplies (PFC)
- Lighting
  - High-intensity discharge (HID)
  - Fluorescent ballast lighting
- Industrial







<b>ABSOLUTE MAXIMUM RATINGS</b> (T <sub>C</sub> = 25 °C, unless otherwise noted)						
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage		$V_{DS}$	600	V		
Gate-Source Voltage			$V_{GS}$	± 30	V	
Continuous Drain Current (T <sub>J</sub> = 150 °C)	\/ at 10 \/	T <sub>C</sub> = 25 °C	- I <sub>D</sub>	20		
	V <sub>GS</sub> at 10 V	$T_C = 25 ^{\circ}C$ $T_C = 100 ^{\circ}C$		10	Α	
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	62		
Linear Derating Factor				1.67	W/°C	
Single Pulse Avalanche Energy b			E <sub>AS</sub>	485	mJ	
Maximum Power Dissipation			$P_{D}$	205/35	W	
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C		
Drain-Source Voltage Slope	T <sub>J</sub> = 125 °C		37	1//		
Reverse Diode dV/dt <sup>d</sup>		dV/dt	4.5	V/ns		
Soldering Recommendations (Peak Temperature) c	for 10 s			300	°C	

#### Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature.
- b.  $V_{DD}$  = 50 V, starting  $T_J$  = 25 °C, L = 28.2 mH,  $R_g$  = 25  $\Omega$ ,  $I_{AS}$  = 4.5 A.
- c. 1.6 mm from case.
- d.  $I_{SD} \le I_D$ , dI/dt = 100 A/ $\mu s$ , starting  $T_J = 25$  °C.



# DTN20N60SJ/DTP20N60SJ/DTP20N60FSJ

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THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	62	°C/W	
Maximum Junction-to-Case (Drain)	$R_{thJC}$	-	0.7	G/ <b>VV</b>	

PARAMETER	SYMBOL	TES	T CONDITIONS	MIN.	TYP.	MAX.	UNIT
Static		•					•
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		600	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	Reference to 25 °C, I <sub>D</sub> = 1 mA		0.75	-	V/°C
Gate-Source Threshold Voltage (N)	V <sub>GS(th)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250 μA		2	-	4	V
		$V_{GS} = \pm 20 \text{ V}$ $V_{GS} = \pm 30 \text{ V}$		-	-	± 100	nA
Gate-Source Leakage	I <sub>GSS</sub>			-	-	± 1	μΑ
		V <sub>DS</sub> =	$V_{DS} = 600 \text{ V}, V_{GS} = 0 \text{ V}$ $V_{DS} = 520 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 125 \text{ °C}$		-	1	μΑ
Zero Gate Voltage Drain Current	I <sub>DSS</sub>				-	10	
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 8 A	-	0.19	-	Ω
Forward Transconductance	9fs	V <sub>DS</sub> = 30 V, I <sub>D</sub> = 8 A		-	5.6	-	S
Dynamic				•	•		
Input Capacitance	C <sub>iss</sub>	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 100 V, f = 1 MHz		-	1440	-	pF
Output Capacitance	Coss			-	80	-	
Reverse Transfer Capacitance	C <sub>rss</sub>			-	4	-	
Effective Output Capacitance, Energy Related <sup>a</sup>	C <sub>o(er)</sub>	V <sub>DS</sub> = 0 V to 520 V, V <sub>GS</sub> = 0 V		-	63	-	
Effective Output Capacitance, Time Related <sup>b</sup>	C <sub>o(tr)</sub>			-	213	-	
Total Gate Charge	Qg			-	48	96	
Gate-Source Charge	Q <sub>gs</sub>	$V_{GS} = 10 \text{ V}$	$V_{GS} = 10 \text{ V}$ $I_D = 8 \text{ A}, V_{DS} = 520 \text{ V}$		11	-	nC
Gate-Drain Charge	$Q_{gd}$			-	21	-	1
Turn-On Delay Time	t <sub>d(on)</sub>	$V_{DD}$ = 520 V, $I_{D}$ = 8 A, $V_{GS}$ = 10 V, $R_{g}$ = 9.1 $\Omega$		-	18	25	ns
Rise Time	t <sub>r</sub>			-	24	55	
Turn-Off Delay Time	$t_{d(off)}$			-	48	70	
Fall Time	t <sub>f</sub>			-	25	40	
Gate Input Resistance	$R_{g}$	f = 1 MHz, open drain		-	0.8	-	Ω
<b>Drain-Source Body Diode Characteristic</b>	s						
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	-	20	
Pulsed Diode Forward Current	I <sub>SM</sub>			-	-	60	- A
Diode Forward Voltage	V <sub>SD</sub>	T <sub>J</sub> = 25 °C, I <sub>S</sub> = 8 A, V <sub>GS</sub> = 0 V		-	-	1.5	V
Reverse Recovery Time	t <sub>rr</sub>	T <sub>J</sub> = 25 °C, I <sub>F</sub> = I <sub>S</sub> = 8 A, dl/dt = 100 A/μs, V <sub>R</sub> = 400 V		-	475	-	ns
Reverse Recovery Charge	Q <sub>rr</sub>			-	5.8	-	μC
Reverse Recovery Current	I <sub>RBM</sub>			_	35	_	A

#### Notes

- a.  $C_{oss(er)}$  is a fixed capacitance that gives the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ . b.  $C_{oss(tr)}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ .

#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

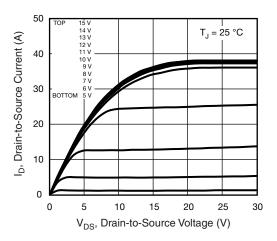


Fig. 1 - Typical Output Characteristics

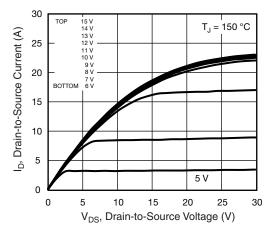


Fig. 2 - Typical Output Characteristics

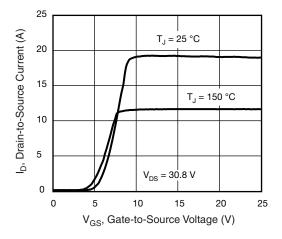


Fig. 3 - Typical Transfer Characteristics

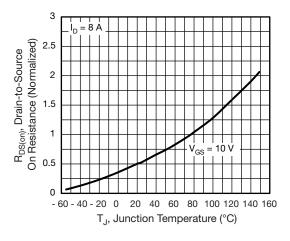


Fig. 4 - Normalized On-Resistance vs. Temperature

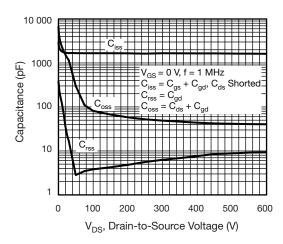


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

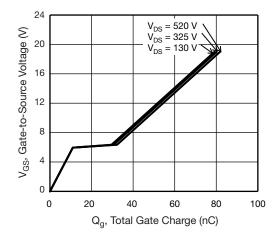


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage



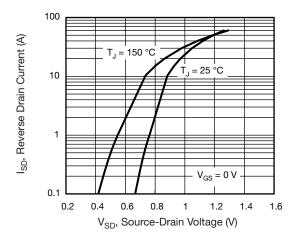


Fig. 7 - Typical Source-Drain Diode Forward Voltage

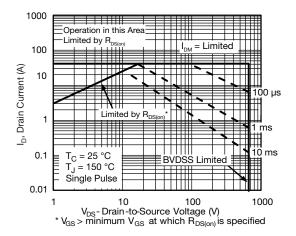


Fig. 8 - Maximum Safe Operating Area

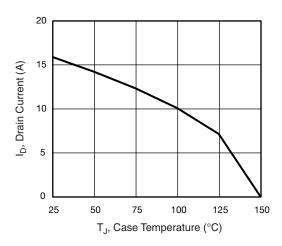


Fig. 9 - Maximum Drain Current vs. Case Temperature

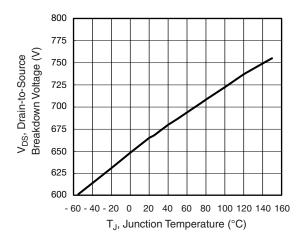


Fig. 10 - Temperature vs. Drain-to-Source Voltage

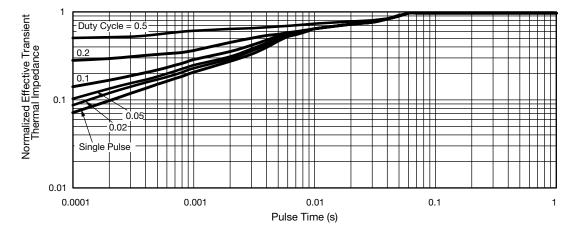


Fig. 11 - Normalized Thermal Transient Impedance, Junction-to-Case

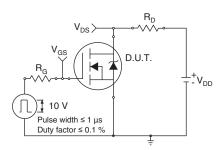


Fig. 12 - Switching Time Test Circuit

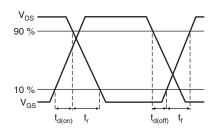


Fig. 13 - Switching Time Waveforms

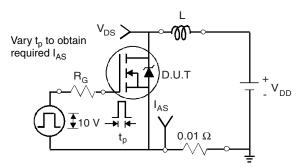


Fig. 14 - Unclamped Inductive Test Circuit

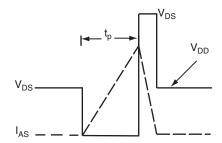


Fig. 15 - Unclamped Inductive Waveforms

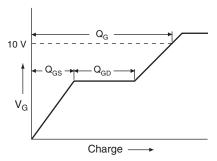


Fig. 16 - Basic Gate Charge Waveform

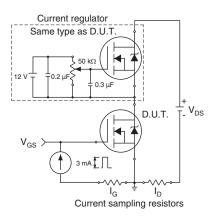
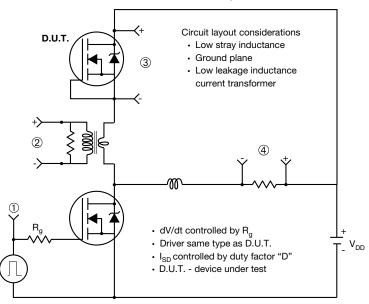


Fig. 17 - Gate Charge Test Circuit

#### Peak Diode Recovery dV/dt Test Circuit



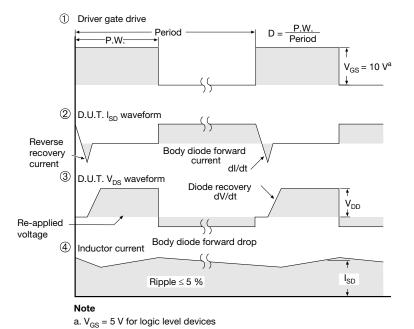


Fig. 18 - For N-Channel





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